



Integrated Device Technology, Inc.

CMOS FLASH A/D CONVERTER

IDT75C48

FEATURES:

- 8-bit resolution
- 30 MSPS conversion rate
- Guaranteed no missing codes
- Pin- and function-compatible with TRW 1048
- Low power consumption: 500mW
- Extended analog input range
- On-chip EDC (Error Detection and Correction)
- Improved output logic HIGH drive, no pull-up needed
- No sample and hold required
- Differential Phase < 1 Degree
- Differential Gain < 2%
- Selectable output formats
- TTL-compatible
- Available in 28-pin Cerdip and LCC
- Military product compliant to MIL-STD-883, Class B
- Standard Military Drawing #5962-88743 is listed for this function

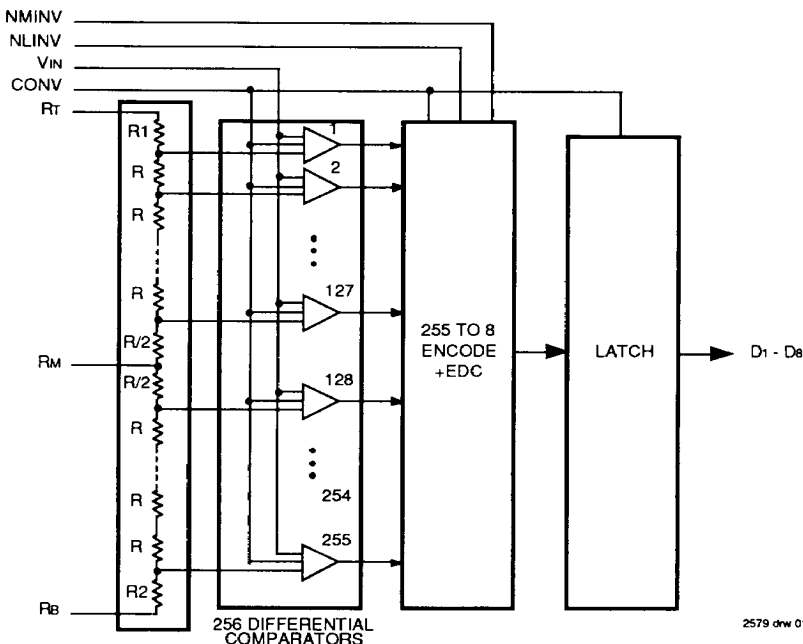
DESCRIPTION:

The IDT75C48 is a 30 MegaSample per Second (MSPS), fully parallel, 8-bit Flash Analog to Digital Converter. The wide input analog bandwidth of 10MHz permits the conversion of analog input signals with full-power frequency components up to this limit with no input sample and hold. Low power consumption due to CEMOS™ processing, virtually eliminates thermal considerations. The IDT75C48 is available in 28-pin plastic and hermetic DIPs and a 28-pin LCC.

The IDT75C48 consists of a reference voltage generator, 255 comparators, encoding and EDC (Error Detection and Correction) logic and an output data register. A single clock starts the conversion process and controls all internal operations. Two control inputs allow the output coding format to be programmed for straight binary or offset two's complement in either the true or inverted form.

The IDT75C48 military Flash A/D Converters are manufactured in compliance with the latest revision of MIL-STD-883, Class B, making them ideally suited to military temperature applications demanding the highest level of performance and reliability.

FUNCTIONAL BLOCK DIAGRAM



CEMOS is a trademark of Integrated Device Technology, Inc.

MILITARY AND COMMERCIAL TEMPERATURE RANGES

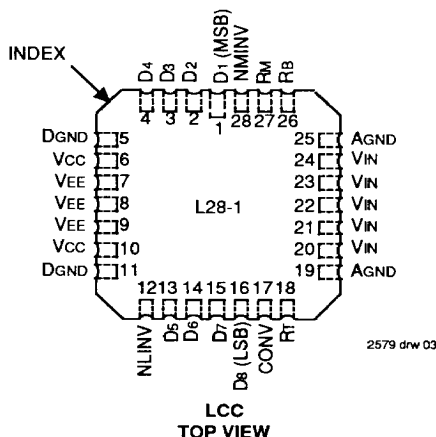
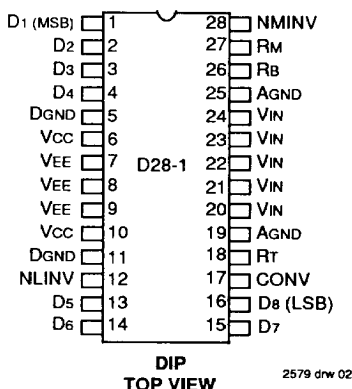
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PIN CONFIGURATIONS



GENERAL INFORMATION

The IDT75C48 has four functional sections: a comparator array, a reference voltage generator, encoding logic with EDC and output logic. The comparator array compares the input signal with 255 reference voltages to produce an N - of - 255 code. This is sometimes called a "Thermometer" code because all of the comparators with their reference voltage less than the input signal will be "on" while those with their reference above the input will be "off".

The reference voltage generator consists of a string of precisely matched resistors which generate the 255 voltages needed by the comparators. The voltages at the ends of the resistor string set the maximum and minimum conversion range and are typically 0V and -2V, respectively.

The encoding logic converts the "Thermometer" code into binary or offset two's complement numbers and can invert either code. Included in the encoding function is Error Detection and Correction logic which ensures that a corrupted Thermometer code is correctly encoded.

The output logic latches and holds the data constant between samples. The output timing is designed for an easy interface to external latches or memories using the same clock as the ADC.

POWER

The IDT75C48 requires two power supply voltages, Vcc and VEE. Typically, VEE = -5.2V and Vcc = +5.0V. Two separate grounds are provided, AGND and DGND, the analog and digital grounds. The difference between AGND and DGND must not exceed $\pm 0.1V$ and all power and ground pins must be connected.

REFERENCE

The IDT75C48 converts analog input signals that are within the range of the reference ($VRB \leq VIN \leq VRT$) into digital form. VRB (Reference Bottom) and VRT (Reference Top) are applied across the reference resistor chain and both must be within

the range of +2.1V to -2.1V. In addition, the voltage applied across the reference resistor chain (VRT-VRB) must be between 1.8V and 2.2V, with VRT more positive than VRB. Nominally, VRT = 0.0V and VRB = -2.0V.

The IDT75C48 provides a midpoint tap, RM, which allows the converter to be adjusted for optimum linearity or a non-linear transfer function. Adjustment of RM is not necessary to meet the linearity specification. Figure 5 shows a circuit which will provide approximately 1/2LSB adjustment of the midpoint. The characteristic impedance of RM is about 170 Ω and this node should be driven from a low impedance source. Any noise introduced at this point will couple directly into the resistor chain, seriously affecting performance.

Due to the unavoidable coupling with the clock and the input signal, RT and RB should provide low AC impedance to ground. For applications with a fixed reference, a bypass capacitor is recommended.

CONTROL

The IDT75C48 provides two function control pins, NMINV and NLINV. These controls are for steady state use and are usually tied to the appropriate voltages. They control the output coding format in either straight binary or offset two's complement. In addition, both formats may be either true or inverted. These pins are active low and perform the functions shown in Figure 1.

CONVERT

The IDT75C48 begins a conversion with every rising edge of the convert signal, CONV. The analog input signal is sampled on the rising edge of CONV, while the outputs of the comparators are encoded on the falling edge. The next rising edge latches the encoder output which is presented on the output pins.

The input sample is taken within 15ns of the rising edge of CONV. This is called ISTO or the Sampling Time Offset. This delay varies by a few nanoseconds from part to part and as a

function of temperature, but the short term uncertainty or jitter is less than 60ps.

If the maximum CONV pulse width HIGH time (TPWH) is exceeded, the accuracy of the input sample may be impaired. The maximum CONV pulse width LOW time (TPWL) may be exceeded, but the digital output data for the sample taken by the previous rising edge of CONV will be meaningless. It is recommended that CONV be held LOW during longer periods of inactivity.

The digital output data is presented at t₀, the Digital Output Delay Time, after the next rising edge of CONV. Previous output data is held for the t_{HO} (Output Hold Time) after the rising edge of CONV to allow for non-critical timing in the

external circuitry. This means that the data for samples N is acquired while the converter is taking sample N + 2.

ANALOG INPUT

The IDT75C48 uses strobed, auto-zeroing, latching comparators. All five analog input pins must be connected together as close to the package as possible.

If the analog input signal is within the reference voltage range, the output will be a binary number between 0 and 255. An input signal above V_{RT} will yield a full-scale positive output while an input below V_{RB} will cause a full-scale negative output.

Step	Range		Binary		Offset Two's	
	-2.0000V FS 7.8431mV/Step	-2.0480V FS 8.000mV/Step	*NMINV=1 NLINV=1	NMINV=0 NLINV=0	NMINV=0 NLINV=1	NMINV=1 NLINV=0
000	0.0000V	0.0000V	00000000	11111111	10000000	01111111
001	-0.0078V	-0.0080V	00000001	11111110	10000001	01111110
⋮	⋮	⋮	⋮	⋮	⋮	⋮
127	-0.9961V	-0.0160V	01111111	10000000	11111111	00000000
128	-1.0039V	-1.0240V	10000000	01111111	00000000	11111111
129	-1.0118V	-1.0320V	10000001	01111110	00000001	11111110
⋮	⋮	⋮	⋮	⋮	⋮	⋮
254	-1.9921V	-2.0320V	11111110	00000001	01111110	10000001
255	-2.0000V	-2.0400V	11111111	00000000	01111111	10000000

*When NMINV and NLINV are both high a 1KΩ series resistor must be inserted between NMINV and V_{cc}.

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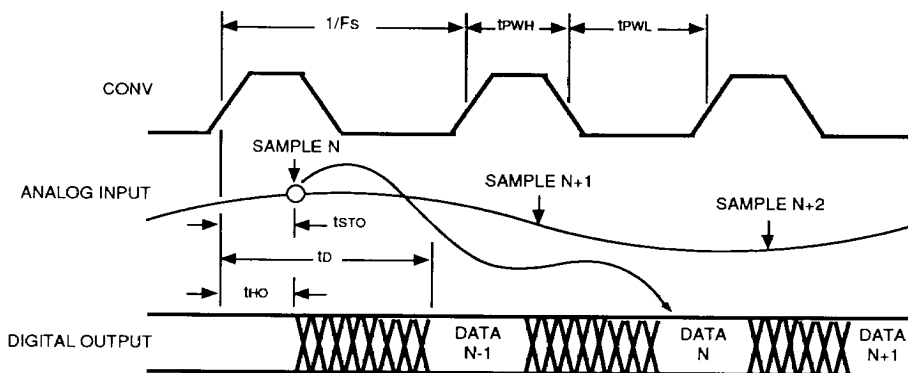
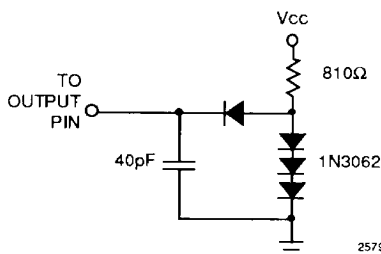


Figure 2. Timing Diagram

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Figure 3. Output Load 1

ABSOLUTE MAXIMUM RATINGS⁽¹⁾

Symbol	Rating	Commercial	Unit
Power Supply			
VCC	Measured to DGND	−0.5 to +7.0	V
VEE	Measured to AGND	+0.5 to −7.0	V
AGND	Measured to DGND	−0.5 to +0.5	V
Input Voltage			
CONV, NMINV, NLINV	Measured to DGND	−0.5 to VCC +0.5	V
VIN, VRT, VRB	Measured to AGND	VCC to VEE	V
VRT	Measured to VRB	−4.0 to +4.0	V
Output			
Applied Voltage ⁽²⁾	Measured to DGND	−0.5 to VCC +0.5	V
Applied Current ^(2, 3, 4)	Externally forced	−20.0 to +20.0	mA
Short Circuit Duration	Single output High to DGND	1.0	S
Temperature			
Operating	Military	−55 to +125	°C
Ambient	Commercial	0 to +70	°C
Storage	Military	−65 to +150	°C
	Commercial	−55 to +125	°C

NOTES:

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- Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability. Absolute Maximum Ratings are limiting values applied individually while all other parameters are within specified operating conditions. Functional operation under any of these conditions is NOT implied.
- Applied voltage must be current limited to specified range.
- Forcing voltage must be limited to specified range.
- Current is specified as conventional current when flowing into the device.

DC ELECTRICAL CHARACTERISTICS

Symbol	Parameter	Test Conditions ⁽¹⁾	Temperature Range						Unit
			Commercial			Military			
			Min.	Nom.	Max.	Min.	Nom.	Max.	
Power Supply									
V _{CC}	Positive Power Supply		4.75	5.0	5.25	4.5	5.0	5.5	V
V _{EE}	Negative Power Supply		-4.9	-5.2	-5.5	-4.9	-5.2	-5.5	V
V _{AGND}	Analog Ground Voltage (ref DGND)		-0.1	0	+0.1	-0.1	0	+0.1	V
I _{CC}	Positive Supply Current	V _{CC} = Max., Static ⁽¹⁾	—	50	70	—	60	80	mA
I _{EE}	Negative Supply Current	V _{EE} = Max., Static ⁽¹⁾	—	-25	-35	—	-25	-35	mA
Digital Inputs (CONV, NMINV, NLINV)									
V _{IL}	Input Voltage, Logic LOW ⁽⁴⁾		-0.5	—	0.8	-0.5	—	0.8	V
V _{IH}	Input Voltage, Logic HIGH ⁽⁴⁾		2.0	—	V _{CC} + 1	2.0	—	V _{CC} + 1	V
I _{IL}	Input Current, Logic LOW	V _{CC} = Max., V _{IL} = 0.5V	—	—	±10	—	—	±10	μA
I _{IH}	Input Current, Logic HIGH	V _{CC} = Max., V _{IH} = 2.4V	—	—	±10	—	—	±10	μA
I _I	Input Current, Max. Input Voltage	V _{CC} = Max., V _I = V _{CC}	—	—	50	—	—	50	μA
C _I	Digital Input Capacitance ⁽⁴⁾	T _A = +25°C, F = 1MHz	—	—	15	—	—	15	pF
Digital Outputs									
V _{OL}	Output Voltage, Logic LOW	V _{CC} = Min., I _{OL} = 4.0mA	—	—	0.5	—	—	0.5	V
V _{OH}	Output Voltage, Logic HIGH	V _{CC} = Min., I _{OH} = 4.0mA	2.4	—	—	2.4	—	—	V
I _{OS}	Output Short Circuit Current	V _{CC} = Max. ⁽²⁾	—	—	-50	—	—	-50	mA
Reference									
V _{RT}	Most Positive Reference Voltage ⁽³⁾		-0.1	0	+0.1	-0.1	0	+0.1	V
V _{RB}	Most Negative Reference Voltage ⁽³⁾		-1.9	-2.0	-2.1	-1.9	-2.0	-2.1	V
V _{RT} - V _{RB}	Reference Voltage Range		1.8	2.0	2.2	1.8	2.0	2.2	V
I _{REF}	Reference Current (RT to RB)	V _{RT} , V _{RB} = Nom.	—	5	9	—	6	10	mA
R _{REF}	Reference Current (RT to RB)	V _{RT} , V _{RB} = Nom.	250	400	—	200	330	—	Ohm
Analog Input									
V _{IN}	Input Voltage Range		V _{RB}	—	V _{RT}	V _{RB}	—	V _{RT}	V
R _{IN}	Equiv. Input Resistance ⁽⁴⁾	V _{RT} , V _{RB} = Nom., V _{IN} = V _{RB}	100	—	—	100	—	—	KOhm
C _{IN}	Equiv. Input Capacitance ⁽⁴⁾	V _{RT} , V _{RB} = Nom., V _{IN} = V _{RB}	—	—	50	—	—	50	pF
I _{CB}	Input Const. Bias Current	V _{EE} = Max.	—	—	10	—	—	10	μA
T _A	Ambient Temperature, Still Air		0	—	70	—	—	—	°C
T _C	Case Temperature		—	—	—	-55	—	+125	°C

NOTES:

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1. Worst case, all digital inputs and outputs LOW.
2. Output HIGH, one pin to ground, one second duration.
3. V_{RT} must be more positive than V_{RB} and the voltage reference must be within the specified range. Although the device is specified and tested with the reference equal to 0V and -2V, the part will operate with V_{RT} up to +2.1V. Likewise, the reference range may vary from 1.2V to 2.6V.
4. This parameter is guaranteed but not tested in production.

AC ELECTRICAL CHARACTERISTICS FOR IDT75C48SX20 (20MHz Version)

Specifications over the DC Electrical range unless otherwise stated.

Symbol	Parameter	Test Conditions		Temperature Range						Unit
				Commercial			Military			
				Min.	Typ.	Max.	Min.	Typ.	Max.	
FS	Conversion Rate	VCC = Min., VEE = Min.		20	30	—	20	30	—	MSPS
TPWL	CONV, Pulse Width LOW ⁽³⁾			18	—	100,000	18	—	100,000	ns
TPWH	CONV, Pulse Width HIGH ⁽³⁾			22	—	20,000	22	—	20,000	ns
ISTO	Sampling Time Offset	VCC = Min., VEE = Min.		0	—	10	0	—	15	ns
EAP	Aperture Error ⁽⁴⁾			—	—	60	—	—	60	ps
tD	Digital Output Delay	VCC = Min., VEE = Min., Load 1		—	—	30	—	—	35	ns
tHO	Digital Output Hold Time	VCC = Min., VEE = Min., Load 1		5	—	—	5	—	—	ns
ELI	Linearity Error, Integral	VRT,	1/2 LSB ⁽²⁾	—	—	0.2	—	—	0.2	%FS
		VRB = Nom.	3/4 LSB ⁽²⁾	—	—	0.3	—	—	0.3	%FS
ELD	Linearity Error, Differential	VRT, VRB = Nom.		—	—	0.2	—	—	0.2	%FS
CS	Code Size ⁽¹⁾			25	100	175	25	100	175	%Nom
EOT	Offset Error, Top	VIN = midpoint code 0		—	10	45	—	10	45	mV
EOB	Offset Error, Bottom	VIN = midpoint code 255		—	–10	–30	—	–10	–30	mV
TCO	Offset Error, Temperature Coefficient ⁽⁴⁾	VIN = VRB		—	—	±20	—	—	±20	µV/°C
BW	Bandwidth, Full Power Input			7	12	—	5	10	—	MHz
TTR	Transient Response, Full Scale ⁽⁵⁾			—	—	20	—	—	20	nS
SNR	Signal to Noise Ratio	20 MSPS Conversion Rate, 10 MHz Bandwidth								
	Peak Signal/RMS Noise	1.248 MHz Input		54	56	—	53	55	—	dB
		2.438 MHz Input		53	56	—	52	55	—	dB
	RMS Signal/RMS Noise	1.248 MHz Input		45	47	—	44	46	—	dB
2.438 MHz Input		44	47	—	43	46	—	dB		
NPR	Noise Power Ratio	DC to 8 MHz White Noise Bandwidth 4 Sigma Loading 1.248 MHz Slot 20 MSPS Conversion Rate		36.5	39	—	36.5	39	—	dB
DP	Differential Phase Error	Fs = 4 x NTSC		—	.5	1	—	.5	1	Degree
DG	Differential Gain Error	Fs = 4 x NTSC		—	1	2	—	1	2	%

NOTES:

- Guarantees no missing codes.
- See the ordering information section regarding the part number designation.
- No damage to the part will occur if the Max. times are exceeded. See the Convert section for more information about the Conv Max. time limitations.
- This parameter is guaranteed but not tested in production.

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AC ELECTRICAL CHARACTERISTICS FOR IDT75C48SX30 (30MHz Version)

Specifications over the DC Electrical range unless otherwise stated.

Symbol	Parameter	Test Conditions		Temperature Range						Unit
				Commercial			Military			
				Min.	Typ.	Max.	Min.	Typ.	Max.	
FS	Conversion Rate	VCC = Min., VEE = Min.		30	40	—	30	40	—	MSPS
TPWL	CONV, Pulse Width LOW			14	—	100,000	14	—	100,000	ns
TPWH	CONV, Pulse Width HIGH			14	—	20,000	14	—	20,000	ns
tSTO	Sampling Time Offset	VCC = Min., VEE = Min.		0	—	10	0	—	15	ns
EAP	Aperture Error ⁽⁴⁾			—	—	60	—	—	60	ps
tD	Digital Output Delay	VCC = Min., VEE = Min., Load 1		—	—	25	—	—	28	ns
tHO	Digital Output Hold Time	VCC = Min., VEE = Min., Load 1		5	—	—	5	—	—	ns
ELI	Linearity Error, Integral	VRT,	3/4 LSB ⁽²⁾	—	—	0.3	—	—	0.3	%FS
		VRB = Nom.	1 LSB ⁽²⁾	—	—	0.4	—	—	0.4	%FS
ELD	Linearity Error, Differential	VRT, VRB = Nom.		—	—	0.2	—	—	0.2	%FS
CS	Code Size ⁽¹⁾			25	100	175	25	100	175	%Nom
EOT	Offset Error, Top	VIN = midpoint code 0		—	10	45	—	10	45	mV
EOB	Offset Error, Bottom	VIN = midpoint code 255		—	–10	–30	—	–10	–30	mV
Tco	Offset Error, Temperature Coefficient ⁽⁴⁾	VIN = VRB		—	—	±20	—	—	±20	μV/°C
BW	Bandwidth, Full Power Input			10	13	—	8	10	—	MHz
TR	Transient Response, Full Scale ⁽⁴⁾			—	—	20	—	—	20	nS
SNR	Signal to Noise Ratio	30 MSPS Conversion Rate, 15 MHz Bandwidth								
	Peak Signal/RMS Noise	5 MHz Input		44	48	—	44	48	—	dB
		10 MHz Input		44	48	—	44	48	—	dB
	RMS Signal/RMS Noise	5 MHz Input		35	39	—	35	39	—	dB
		10 MHz Input		35	39	—	35	39	—	dB
NPR	Noise Power Ratio	DC to 15 MHz White Noise Bandwidth 4 Sigma Loading 5 MHz Slot 30 MSPS Conversion Rate		—	—	—	—	—	—	dB
DP	Differential Phase Error	Fs = 4 x NTSC		—	.5	1	—	.5	1	Degree
DG	Differential Gain Error	Fs = 4 x NTSC		—	1	2	—	1	2	%

NOTES:

- Guarantees no missing codes.
- See the ordering information section regarding the part number designation.
- No damage to the part will occur if the Max. times are exceeded. See the Convert section for more information about the Conv Max. time limitations.
- This parameter is guaranteed but not tested in production.

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CALIBRATION

The calibration of the IDT75C58 involves the setting of the 1st and 255th comparator thresholds to the desired voltages. This is done by varying the top and bottom voltages on the reference resistor chain, VRT and VRB, to compensate for any internal offsets. Assuming a nominal 0V to -2V reference range, apply -0.0039V (1/2 LSB from 0V) to the analog input, continuously strobe the device and adjust VRT until the OVFL output toggles between 0 and 1. To adjust the first comparator, apply -1.996V (1/2 LSB from -2V) to the analog input and adjust VRB until the converter output toggles between the codes 0 and 1.

The offset errors are caused by the parasitic resistance between the package pins and the actual resistor chain on-chip and are shown as R1 and R2 in the Functional Block Diagram. The offset errors, EOT and EOB, are specified in the AC Electrical Characteristics and indicate the degree of adjustment needed.

The previously described calibration scheme requires that both ends of the reference resistor chain be adjustable, i.e. be driven by operational amplifiers. A simpler method is to connect the top of the resistor chain, RT, to analog ground or 0V and to adjust this end of the range with the input buffer offset control. The offset error at the bottom of the resistor chain results in a slight gain error which can be compensated for by varying the voltage applied to RB. This is a preferred method for gain adjustment since it is not the input signal path. See Figure 5 for a detailed circuit diagram of this method.

TYPICAL INTERFACE

Figure 5 shows a typical application example for the IDT75C58. The analog input amplifier is a bipolar wideband operational amplifier whose low impedance output directly drives the A/D Converter. The input buffer amplifier is configured with a gain of minus two which will convert a standard video input signal (1V p-p) to the recommended 2V converter input range. Both VIN pins are connected together as close to the package as possible and the input buffer feedback loop is closed at this point. Bipolar inputs, as well as the calibration of the reference top, are accomplished using the offset control. A band-gap reference is used to provide a stable voltage for both the offset and gain control. A variable capacitor in the input buffer feedback loop allows optimization of either the step or the frequency response and may be replaced by a fixed value in the final version of the printed circuit board.

To ensure operation to the rated specifications, proper decoupling is needed. The bypass capacitors should be located close to the chip with the shortest lead lengths possible. Massive ground planes are recommended. If separate digital and ground planes are used, they should be connected together at one point close to the IDT75C58.

The bottom reference voltage, VRB, is supplied by an inverting amplifier buffered by a PNP transistor. The transistor provides a low impedance source and is necessary to provide the current flowing through the resistor chain. The bottom reference voltage may be adjusted to cancel the gain error introduced by the offset voltage, EOB, as discussed in the calibration section.

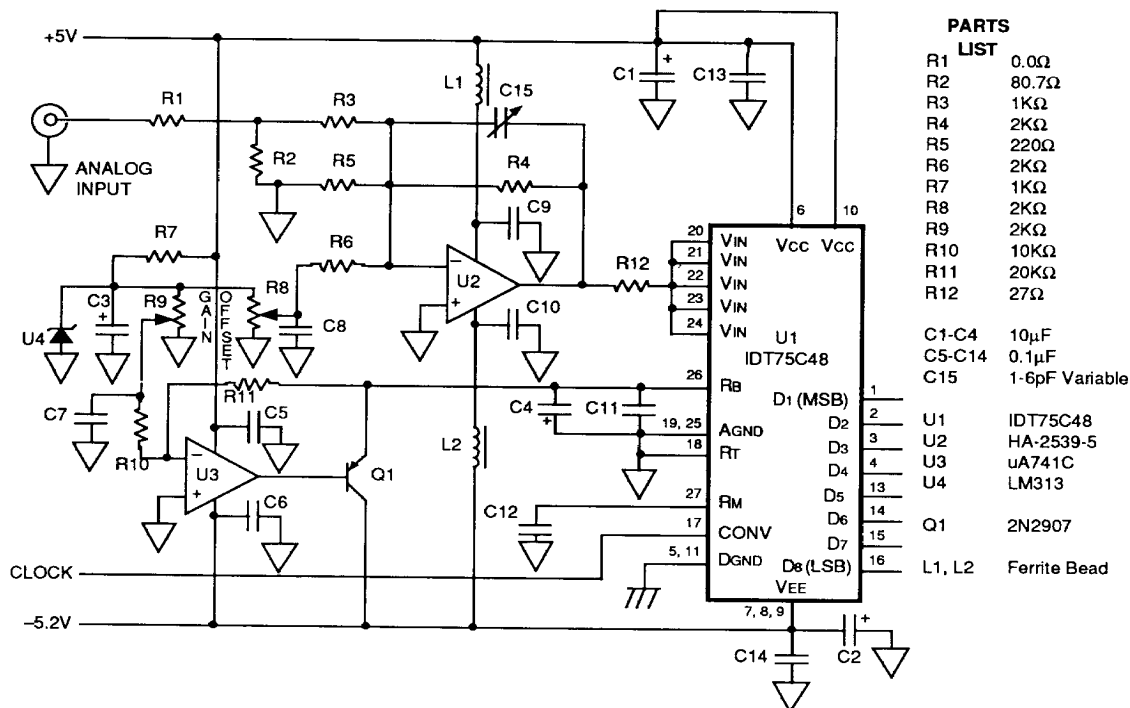


Figure 4. Application Example

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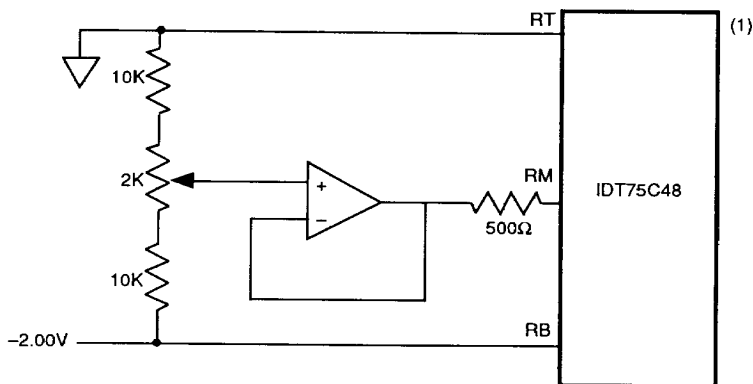


Figure 5. Mid-Point Adjust

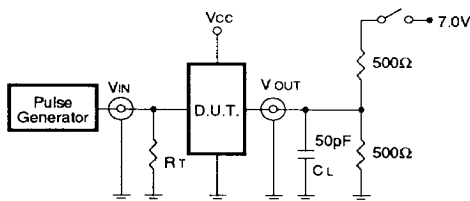
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NOTE:

1. When NMINV and NLINV are both HIGH a 1KΩ series resistor must be inserted between NMINV and Vcc.

TEST CIRCUITS AND WAVEFORMS

TEST CIRCUITS FOR ALL OUTPUTS



SWITCH POSITION

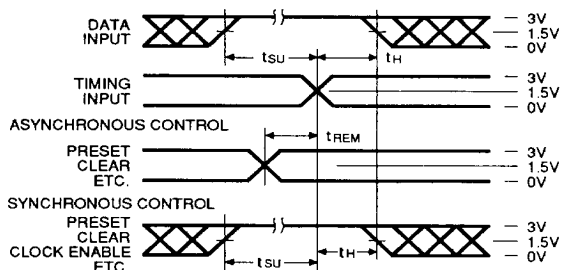
Test	Switch
Open Drain Disable Low Enable Low	Closed
All Other Outputs	Open

DEFINITIONS:

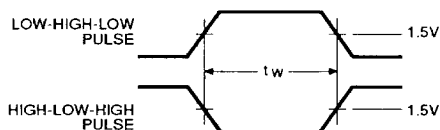
CL = Load capacitance: includes jig and probe capacitance.
RT = Termination resistance: should be equal to ZOUT of the Pulse Generator.

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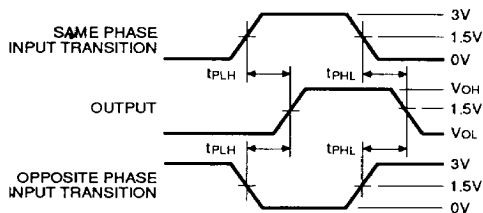
SET-UP, HOLD AND RELEASE TIMES



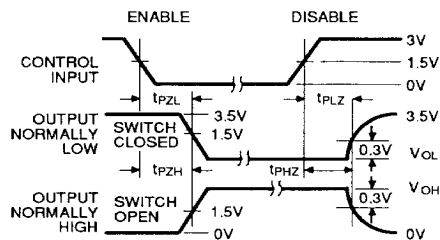
PULSE WIDTH



PROPAGATION DELAY



ENABLE AND DISABLE TIMES

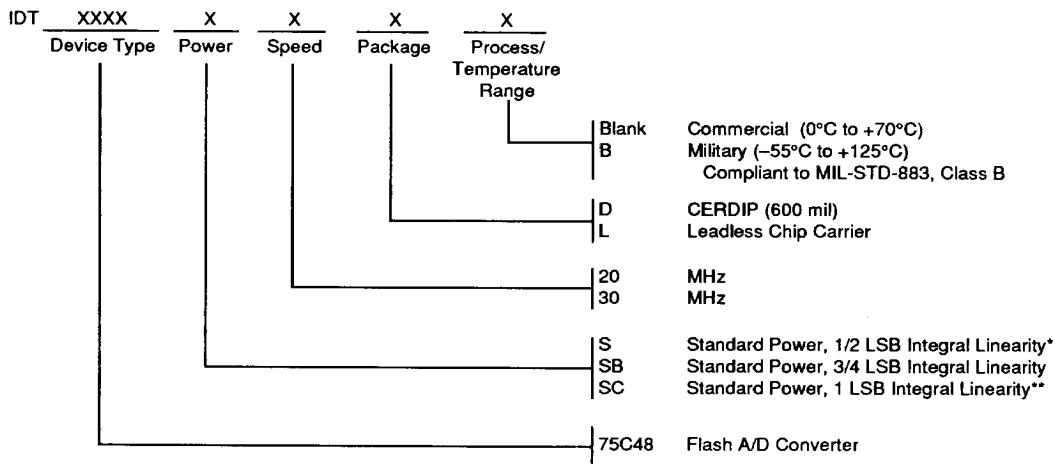


NOTES

- Diagram shown for input Control Enable-LOW and input Control Disable-HIGH.
- Pulse Generator for All Pulses: Rate ≤ 1.0 MHz; $Z_o \leq 50\Omega$; $t_f \leq 2.5$ ns; $t_r \leq 2.5$ ns.

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ORDERING INFORMATION



* 20 MHz Version only

** 30 MHz Version only

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